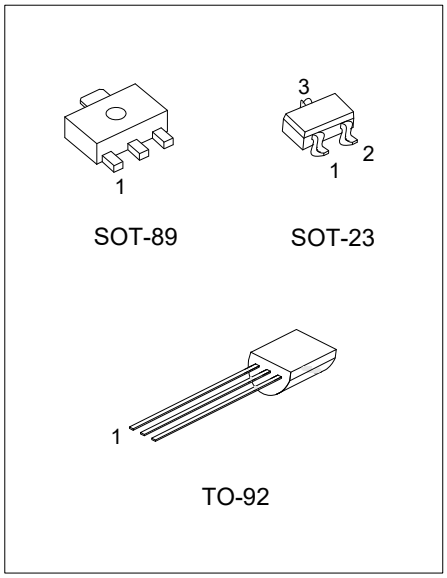
02N40-TA

Power MOSFET

0.2A, 400V N-CHANNEL POWER MOSFET



SOT-89 SOT-23

TO-92

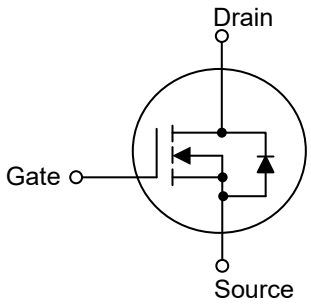
■ DESCRIPTION

The UTC **02N40-TA** is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

* $R_{DS(ON)} \leq 14\ \Omega$ @ V_{GS}=10V, I_D=0.1A
* High breakdown voltage

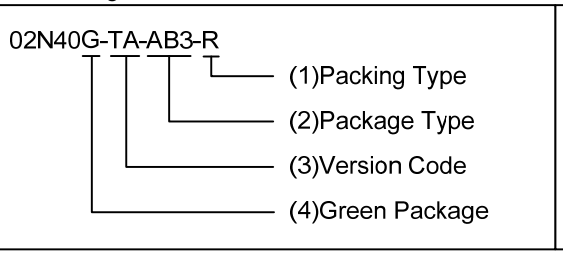
■ SYMBOL



■ ORDERING INFORMATION

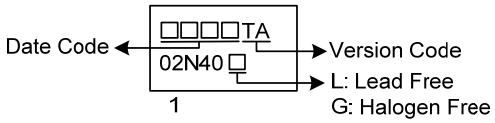
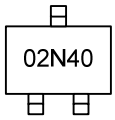
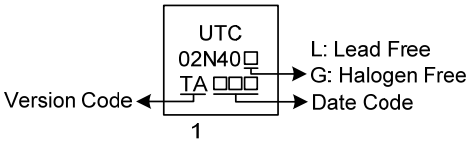
Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
02N40L-TA-AB3-R	02N40G-TA-AB3-R	SOT-89	G	D	S	Tape Reel
02N40L-TA-AE3-R	02N40G-TA-AE3-R	SOT-23	G	S	D	Tape Reel
02N40L-TA-T92-B	02N40G-TA-T92-B	TO-92	G	D	S	Tape Box
02N40L-TA-T92-K	02N40G-TA-T92-K	TO-92	G	D	S	Bulk

Note: Pin Assignment: G: Gate D: Drain S: Source



(1) R: Tape Reel, B: Tape Box, K: Bulk
(2) AB3: SOT-89, AE3: SOT-23, T92: TO-92
(3) Version TA
(4) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING

PACKAGE	MARKING
SOT-89	
SOT-23	
TO-92	

■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	400	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I_D	0.2	A
	Pulsed	I_{DM}	1.2	A
Peak Diode Recovery dv/dt (Note 3)		dv/dt	3.3	V/ns
Power Dissipation	SOT-89	P_D	1.5	W
	SOT-23		0.4	W
	TO-92		1	W
Junction Temperature		T_J	150	°C
Storage Temperature Range		T_{STG}	-55 ~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. I_{SD} ≤ 0.2A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, T_J ≤ T_{JMAX}, T_J = 25°C.

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	SOT-89	θ_{JA}	130	°C/W
	SOT-23		325	°C/W
	TO-92		160 (Note)	°C/W
Junction to Case	SOT-89	θ_{JC}	83.3	°C/W
	SOT-23		312	°C/W
	TO-92		125 (Note)	°C/W

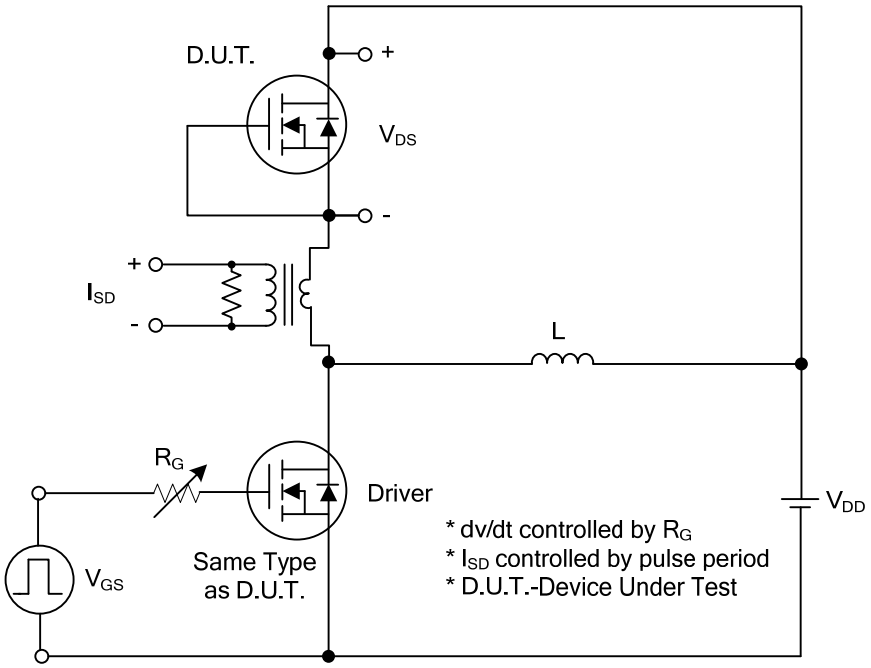
Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS (T_A=25°C, unless otherwise specified)

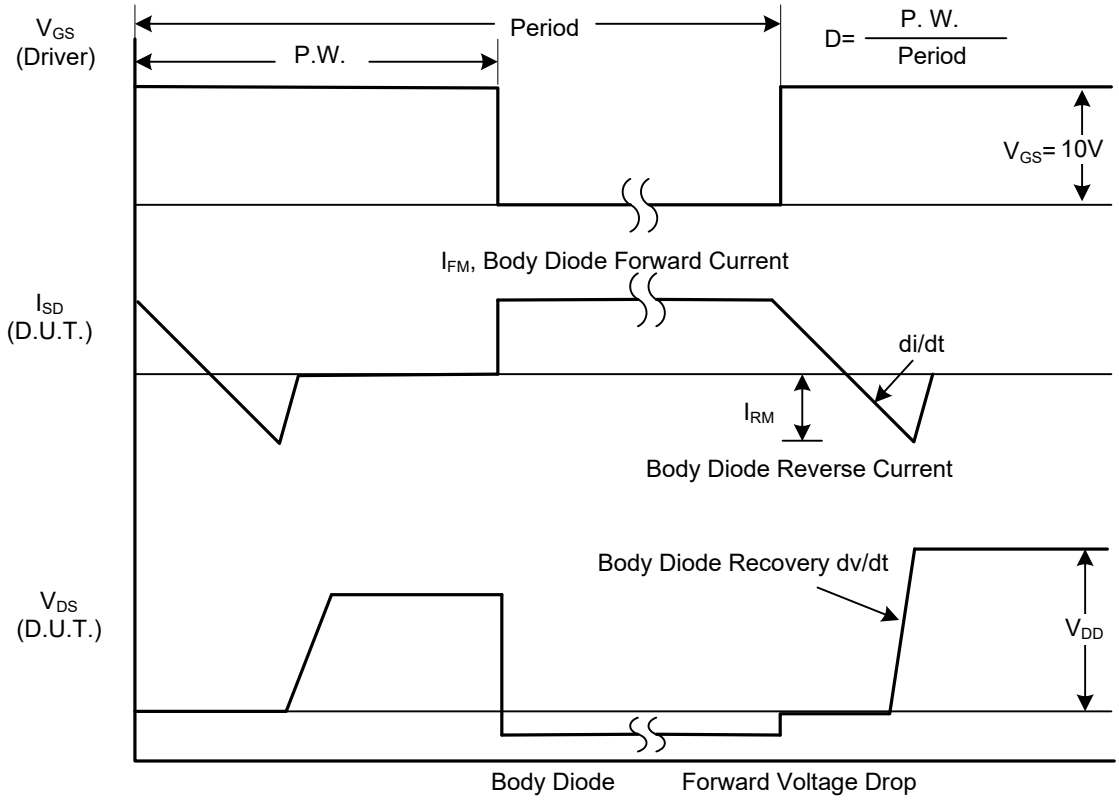
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I_D=250μA, V_{GS}=0V	400			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=400V, V_{GS}=0V			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS}=+30V, V_{DS}=0V			+100	nA
	Reverse		V_{GS}=-30V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	2.0		4.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=0.1A			14	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=25V, f=1.0MHz		59		pF
Output Capacitance		C_{OSS}			13		pF
Reverse Transfer Capacitance		C_{RSS}			2.2		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	V_{DS}=320V, V_{GS}=10V, I_D=0.2A (Note1,2)		8		nC
Gate to Source Charge		Q_{GS}			1		nC
Gate to Drain Charge		Q_{GD}			3		nC
Turn-ON Delay Time		$t_{D(ON)}$	V_{DS}=100V, V_{GS}=10V, I_D=0.2A, R_G=25Ω (Note1,2)		4.2		ns
Rise Time		t_R			17		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			20		ns
Fall-Time		t_F			98		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				0.2	A
Maximum Body-Diode Pulsed Current		I_{SM}				1.2	A
Drain-Source Diode Forward Voltage		V_{SD}	I_S=0.2A, V_{GS}=0V			1.4	V
Reverse Recovery Time		t_{rr}	V_{GS}=0V, I_S=0.2A, di/dt=100A/μs		77		ns
Reverse Recovery Charge		Q_{rr}			92		nC

Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating temperature typical characteristics.

■ TEST CIRCUITS AND WAVEFORMS

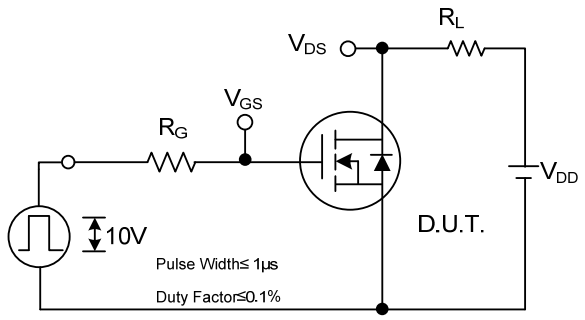


Peak Diode Recovery dv/dt Test Circuit

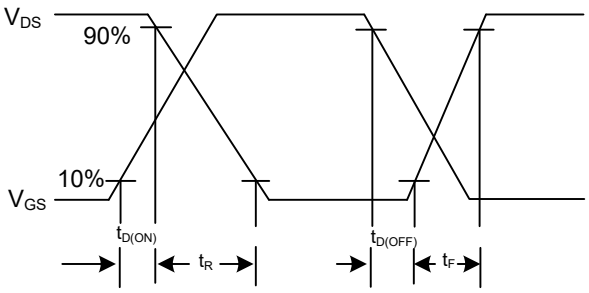


Peak Diode Recovery dv/dt Waveforms

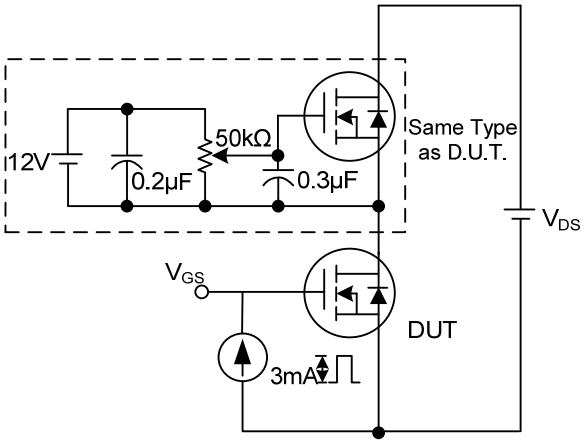
■ TEST CIRCUITS AND WAVEFORMS



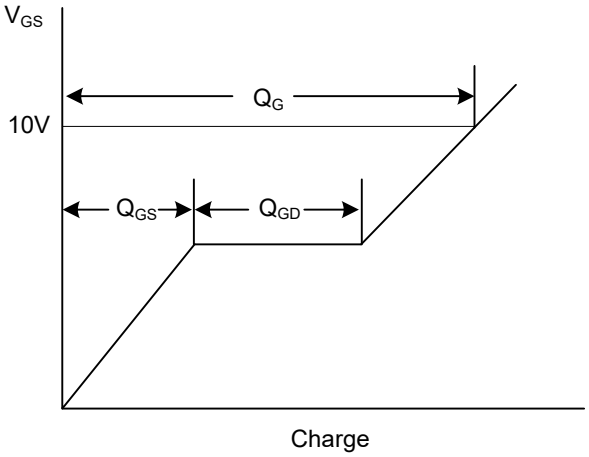
Switching Test Circuit



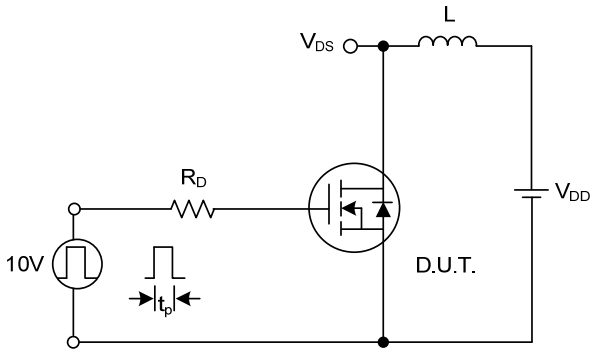
Switching Waveforms



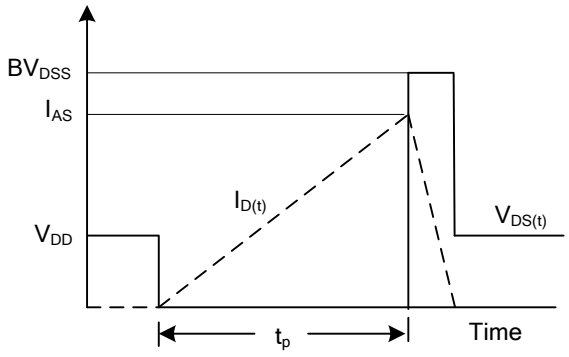
Gate Charge Test Circuit



Gate Charge Waveform

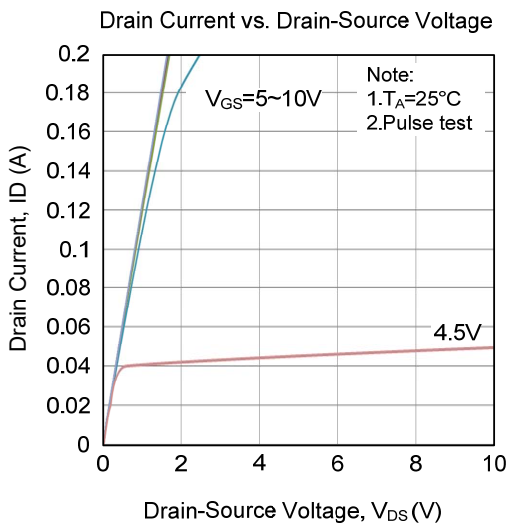


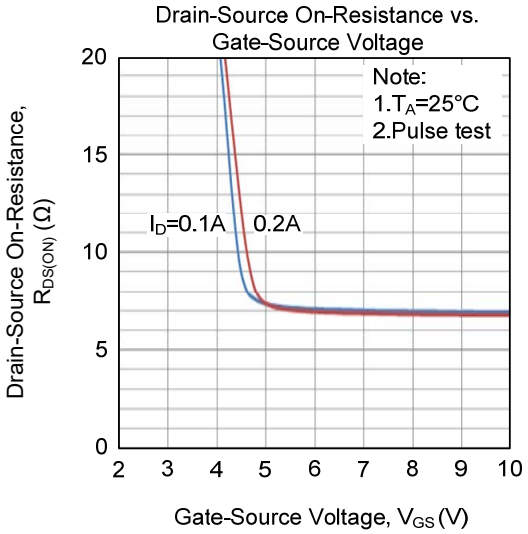
Unclamped Inductive Switching Test Circuit

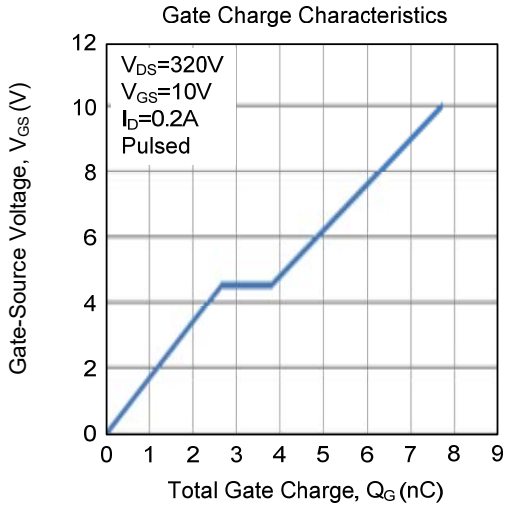


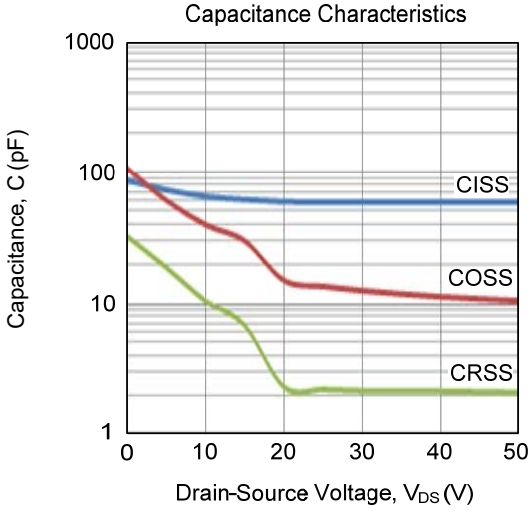
Unclamped Inductive Switching Waveforms

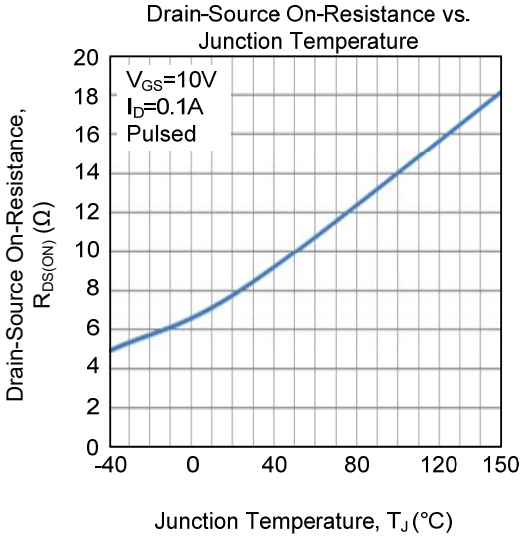
■ TYPICAL CHARACTERISTICS

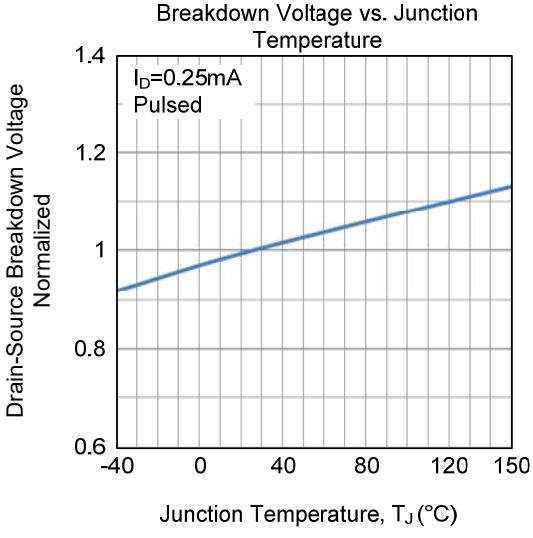




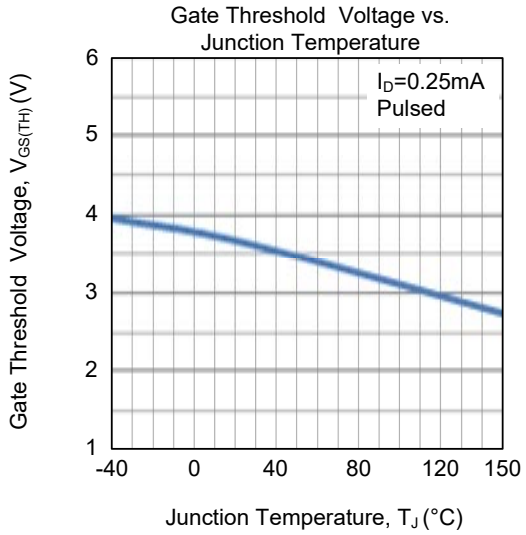


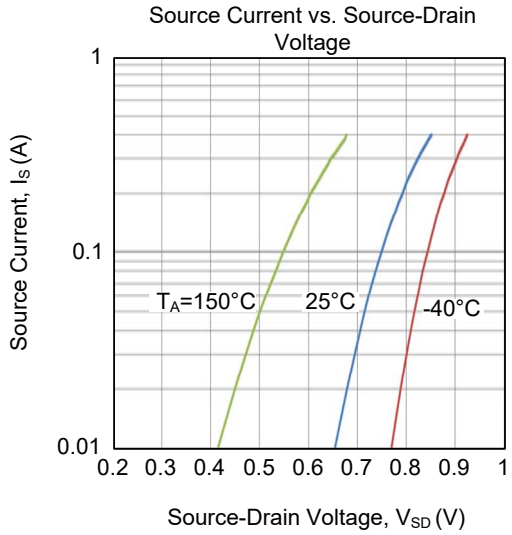


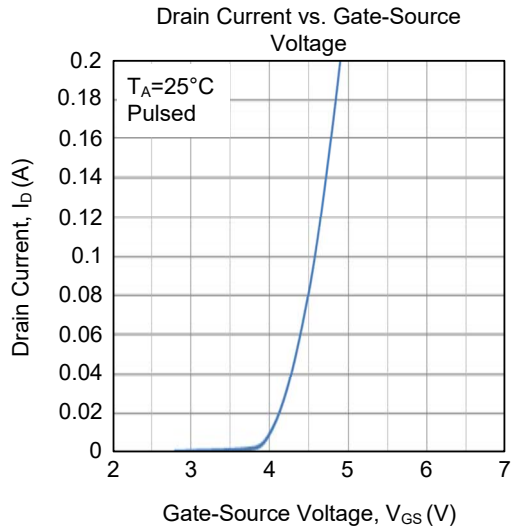


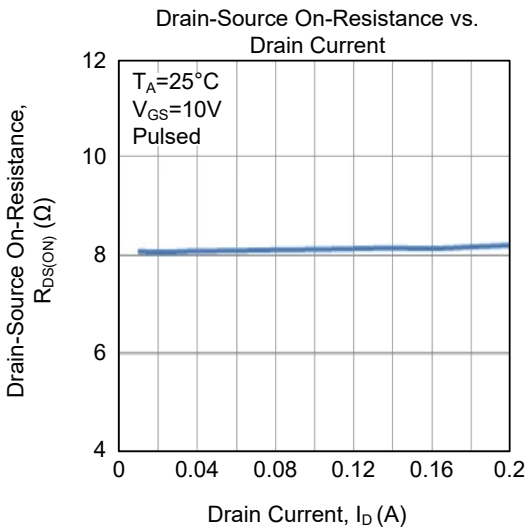


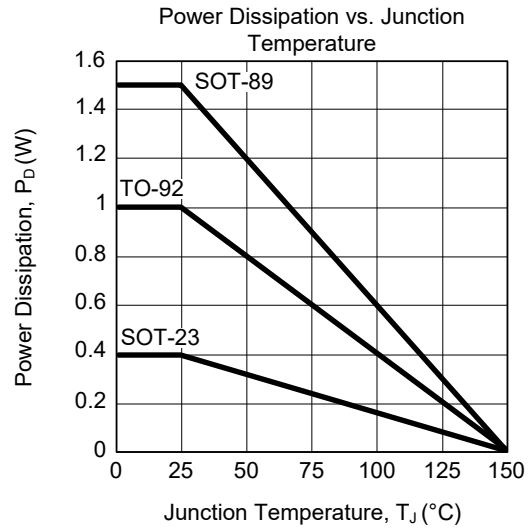
■ TYPICAL CHARACTERISTICS (Cont.)

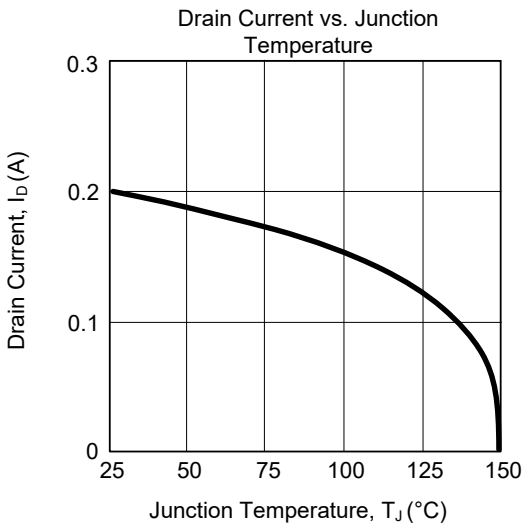












■ TYPICAL CHARACTERISTICS (Cont.)